SIMTEK6349

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Chihiro Araki

Patent No. 6.809.532

Issued: October 26, 2004

App. No.: 10/063,869

Filed: May 21, 2002

Conf. No.: 2434

Title: INSPECTION METHOD AND

INSPECTION APPARATUS FOR SEMICONDUCTOR CIRCUIT

Examiner: T. Nguyen
Art Unit: 2829

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

FOLLOW UP STATUS LETTER

Dear Sir:

A request for a Certificate Of Correction was filed regarding this patent on February 28, 2005, and this appears in the PARE record. A Status Letter was filed on March 30, 2007 which also appears in PARE. However no action has been taken on this request and this is to follow up and seek an answer, with the assistance of the Commissioner's Office if no response is forthcoming.

Respectfully submitted:

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